

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

T.-Y. Chang et al.

Attorney Docket No.: SIPT121256

Application No.: 10/601,709

Group Art Unit: ---

Filed:

June 19, 2002

Examiner: ---

Title:

INTEGRATED CIRCUIT DEVICE WITH A BUILT-IN DETECTING CIRCUIT FOR DETECTING MAXIMUM MEMORY ACCESS TIME OF

AN EMBEDDED MEMORY

INFORMATION DISCLOSURE STATEMENT

TO THE COMMISSIONER FOR PATENTS:

Applicants are aware of the information listed in the attached form that may be material to the prosecution of the above-identified patent application.

- X Copies of the listed patents, publications, and other information are enclosed for the Examiner's use.
- X Pursuant to 37 C.F.R. § 1.97(b), this Information Disclosure Statement is being filed within three months of the filing date of the national application (other than a CPA), within three months of the date of entry of the national stage as set forth in 37 C.F.R. § 1.491 in an international application, before the mailing date of a first Office Action on the merits, or before the mailing date of a first Office Action after the filing of an RCE.

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LAW OFFICES OF CHRISTENSEN O'CONNOR JOHNSON KINDNESS"** 1420 Filth Avenue Suite 2800 Seattle, Washington 98101 206.682.8100 3. X The Commissioner is hereby authorized to charge any fees under 37 C.F.R. §§ 1.16, 1.17 and 1.18 which may be required during the entire pendency of the application, or credit any overpayment, to Deposit Account No. 03-1740. This authorization also hereby includes a request for any extensions of time of the appropriate length required upon the filing of any reply during the entire prosecution of this application. A copy of this document is enclosed.

Respectfully submitted,

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I hereby certify that this correspondence is being deposited with the U.S. Postal Service in a sealed envelope as first class mail with postage thereon fully prepaid and addressed to Mail Stop Patent Application, Commissioner for Patents, P.O. Box 1450. Alexandria, VA 22313-1450, on the below date.

Date: August 29, 2003

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TED BY APPLICANT(S) THAT MAY BE MATERIAL TO THE PROSECUTION OF THE SUBJECT APPLICATION

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INTEGRATED CIRCUIT DEVICE WITH A BUILT-IN DETECTING

CIRCUIT FOR DETECTING MAXIMUM MEMORY ACCESS TIME OF AN

EMBEDDED MEMORY

U.S. PATENT DOCUMENTS

*Examine	r Cite		Kind	Date		
Initials	No.	Document No.,	Code	(mm/dd/yyyy)	Name	
	_ U1	6,424,583		07/23/2002	Sung et al.	

FOREIGN PATENT DOCUMENTS

				D 111 // D /		English	
*Examiner Cite		Kind	Publication Date		Abstract	Translation	
Initial	No.	Document No.	Code	(mm/dd/yyyy)	Country	Provided	Provided

None.

OTHER INFORMATION

(Including Author, Title, Date, Pertinent Pages, Etc.)

*Examiner Initial	Cite No.				
	O1	Sung and Wu, A Method of Embedded Memory Access Time Measurement, IEEE, 462-465 (2001)			
	O2	Lee, Hsiao and Chang, An Access Timing Measurement Unit of Embedded Memory, IEEE, 104-109 (2002)			
Examiner		Date Considered			

*Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. SIL:DDP

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